

# Herbert Hutter

## List of Publications by Year in descending order

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143  
papers

2,722  
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201674

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148  
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docs citations

148  
times ranked

3460  
citing authors

#	ARTICLE	IF	CITATIONS
1	Study on the Ion Migration of Silver Ions from Aqueous Solution in Epoxy-Based Molding Compounds by TOF-SIMS Measurements. ECS Journal of Solid State Science and Technology, 2022, 11, 024006.	1.8	0
2	Acquisition of artifact free alkali metal distributions in SiO <sub>2</sub> by ToF-SIMS Cs + depth profiling at low temperatures. Surface and Interface Analysis, 2021, 53, 675-680.	1.8	1
3	Study of metabolism and identification of productive regions in filamentous fungi via spatially resolved time-of-flight secondary ion mass spectrometry. Analytical and Bioanalytical Chemistry, 2020, 412, 2081-2088.	3.7	4
4	Strain-induced structure and oxygen transport interactions in epitaxial La <sub>0.6</sub> Sr <sub>0.4</sub> CoO <sub>3</sub> thin films. Communications Materials, 2020, 1, .	6.9	8
5	Accelerated Ionic Motion in Amorphous Memristor Oxides for Nonvolatile Memories and Neuromorphic Computing. Advanced Functional Materials, 2019, 29, 1804782.	14.9	51
6	Designing properties of (Na <sub>1/2</sub> Bi <sub>x</sub> )TiO <sub>3</sub> -based materials through A-site non-stoichiometry. Journal of Materials Chemistry C, 2018, 6, 738-744.	5.5	37
7	Influence of surface atomic structure demonstrated on oxygen incorporation mechanism at a model perovskite oxide. Nature Communications, 2018, 9, 3710.	12.8	54
8	Differences between Li, Na, and K migration in thin SiO <sub>2</sub> films during ToF-SIMS O <sub>2</sub> <sup>+</sup> depth profiling. Journal of Vacuum Science and Technology B: Nanotechnology and Microelectronics, 2018, 36, .	1.2	2
9	Interplay of Grain Size Dependent Electronic and Ionic Conductivity in Electrochemical Polarization Studies on Sr-Doped LaMnO <sub>3</sub> (LSM) Thin Film Cathodes. Journal of the Electrochemical Society, 2018, 165, F702-F709.	2.9	12
10	Solar wind sputtering of wollastonite as a lunar analogue material – Comparisons between experiments and simulations. Icarus, 2018, 314, 98-105.	2.5	30
11	Potassium self-diffusion in a K-rich single-crystal alkali feldspar. Physics and Chemistry of Minerals, 2017, 44, 345-351.	0.8	14
12	Large O <sub>2</sub> Cluster Ions as Sputter Beam for ToF-SIMS Depth Profiling of Alkali Metals in Thin SiO <sub>2</sub> Films. Analytical Chemistry, 2017, 89, 2377-2382.	6.5	14
13	Experimental Design for Voltage Driven Tracer Incorporation and Diffusion Studies on Oxide Thin Film Electrodes. Journal of the Electrochemical Society, 2017, 164, F809-F814.	2.9	9
14	Dislocations Accelerate Oxygen Ion Diffusion in La <sub>0.8</sub> Sr <sub>0.2</sub> MnO <sub>3</sub> Epitaxial Thin Films. ACS Nano, 2017, 11, 11475-11487.	14.6	80
15	Metal assisted photochemical etching of 4H silicon carbide. Journal Physics D: Applied Physics, 2017, 50, 435301.	2.8	15
16	Oxygen Vacancies in Fast Lithium-Ion Conducting Garnets. Chemistry of Materials, 2017, 29, 7189-7196.	6.7	63
17	Stacked Layers of Different Porosity in 4H SiC Substrates Applying a Photoelectrochemical Approach. Journal of the Electrochemical Society, 2017, 164, E337-E347.	2.9	7
18	The Sulphur Poisoning Behaviour of Gadolinia Doped Ceria Model Systems in Reducing Atmospheres. Materials, 2016, 9, 649.	2.9	21

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19	The Effect of Acceptor and Donor Doping on Oxygen Vacancy Concentrations in Lead Zirconate Titanate (PZT). <i>Materials</i> , 2016, 9, 945.	2.9	66
20	Water-Induced Decoupling of Tracer and Electrochemical Oxygen Exchange Kinetics on Mixed Conducting Electrodes. <i>Journal of Physical Chemistry Letters</i> , 2016, 7, 2826-2831.	4.6	24
21	Investigation of Electric Field Induced Ion Migration in Semiconductor Encapsulation Materials without the Interference of Electron Conductivity. <i>ECS Journal of Solid State Science and Technology</i> , 2016, 5, N72-N76.	1.8	3
22	Insertion behavior of sodium and potassium ions into thin CVD $\text{SiO}_x$ layers by means of a triangular voltage sweep method. <i>Surface and Interface Analysis</i> , 2016, 48, 636-649.	1.8	1
23	Influence of oxygen impurities on growth morphology, structure and mechanical properties of Ti-Al-N thin films. <i>Thin Solid Films</i> , 2016, 603, 39-49.	1.8	21
24	The Chemical Capacitance as a Fingerprint of Defect Chemistry in Mixed Conducting Oxides. <i>Acta Chimica Slovenica</i> , 2016, 63, 509-518.	0.6	10
25	Apparent Oxygen Uphill Diffusion in $\text{La}_{0.8}\text{Sr}_{0.2}\text{MnO}_3$ Thin Films upon Cathodic Polarization. <i>ChemElectroChem</i> , 2015, 2, 1487-1494.	3.4	13
26	Potash-lime-silica glass: protection from weathering. <i>Heritage Science</i> , 2015, 3, .	2.3	13
27	Oxygen Ion Conduction in Bulk and Grain Boundaries of Nominally Donor-Doped Lead Zirconate Titanate (<sc>PZT</sc>): A Combined Impedance and Tracer Diffusion Study. <i>Journal of the American Ceramic Society</i> , 2015, 98, 3259-3269.	3.8	11
28	Rhodium Germanide Schottky Barrier Contacts. <i>ECS Journal of Solid State Science and Technology</i> , 2015, 4, P387-P392.	1.8	2
29	Fast oxygen exchange and diffusion kinetics of grain boundaries in Sr-doped $\text{LaMnO}_3$ thin films. <i>Physical Chemistry Chemical Physics</i> , 2015, 17, 7659-7669.	2.8	92
30	Mapping electrochemically driven gas exchange of mixed conducting $\text{SrTi}_{0.7}\text{Fe}_{0.3}\text{O}_{3-\delta}$ and $\text{Ce}_{0.8}\text{Gd}_{0.2}\text{O}_{1.9}$ thin films by $^{18}\text{O}$ tracer incorporation under reducing atmosphere. <i>Solid State Ionics</i> , 2015, 273, 25-29.	2.7	6
31	The Effect of Mn Co-doping on the Electrochemical Properties of $\text{Gd}_{0.2}\text{Ce}_{0.8}\text{O}_{1.9}$ -d/Pt Model-composite Electrodes. <i>ECS Transactions</i> , 2015, 68, 1509-1516.	0.5	6
32	Modified-Atmospheric Pressure-Matrix Assisted Laser Desorption/Ionization Identification of Friction Modifier Additives Oleamide and Ethoxylated Tallow Amines on Varied Metal Target Materials and Tribologically Stressed Steel Surfaces. <i>Analytical Chemistry</i> , 2015, 87, 11375-11382.	6.5	3
33	Electrochemical properties of $\text{La}_{0.6}\text{Sr}_{0.4}\text{CoO}_{3-\delta}$ thin films investigated by complementary impedance spectroscopy and isotope exchange depth profiling. <i>Solid State Ionics</i> , 2014, 256, 38-44.	2.7	28
34	A novel ToF-SIMS operation mode for sub 100nm lateral resolution: Application and performance. <i>Applied Surface Science</i> , 2014, 289, 407-416.	6.1	81
35	Temperature gradients in microelectrode measurements: Relevance and solutions for studies of SOFC electrode materials. <i>Solid State Ionics</i> , 2014, 268, 82-93.	2.7	28
36	Cation diffusion in $\text{La}_{0.6}\text{Sr}_{0.4}\text{CoO}_{3-\delta}$ below 800 $^{\circ}\text{C}$ and its relevance for Sr segregation. <i>Physical Chemistry Chemical Physics</i> , 2014, 16, 2715.	2.8	104

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37	Sol-gel silica coating for potash-lime-silica stained glass: Applicability and protective effect. <i>Journal of Non-Crystalline Solids</i> , 2014, 390, 45-50.	3.1	15
38	Oxygen vacancy redistribution in $\text{PbZrTi}_{1-x}\text{O}_3$ (PZT) under the influence of an electric field. <i>Solid State Ionics</i> , 2014, 262, 625-629.	2.7	28
39	Comparison of WTi and WTi(N) as diffusion barriers for Al and Cu metallization on Si with respect to thermal stability and diffusion behavior of Ti. <i>Microelectronics Reliability</i> , 2014, 54, 2487-2493.	1.7	26
40	Atmospheric Pressure Matrix-Assisted Laser Desorption/Ionization Mass Spectrometry of Friction Modifier Additives Analyzed Directly from Base Oil Solutions. <i>European Journal of Mass Spectrometry</i> , 2014, 20, 299-305.	1.0	3
41	Correction of topographic artefacts of ToF-SIMS element distributions. <i>Surface and Interface Analysis</i> , 2013, 45, 457-460.	1.8	5
42	Oxygen transport in electroceramics investigated by electrochemical $^{18}\text{O}/^{16}\text{O}$ isotope exchange and ToF-SIMS. <i>Surface and Interface Analysis</i> , 2013, 45, 486-489.	1.8	3
43	ToF-SIMS measurements with topographic information in combined images. <i>Analytical and Bioanalytical Chemistry</i> , 2013, 405, 7161-7167.	3.7	15
44	The relevance of interfaces for oxide ion transport in yttria stabilized zirconia (YSZ) thin films. <i>Physical Chemistry Chemical Physics</i> , 2013, 15, 1097-1107.	2.8	36
45	Tensile Lattice Strain Accelerates Oxygen Surface Exchange and Diffusion in $\text{La}_{1-x}\text{Sr}_x\text{Co}_3$ Thin Films. <i>ACS Nano</i> , 2013, 7, 3276-3286.	14.6	211
46	A novel ToF-SIMS operation mode for improved accuracy and lateral resolution of oxygen isotope measurements on oxides. <i>Journal of Analytical Atomic Spectrometry</i> , 2013, 28, 1080.	3.0	58
47	Mutual Lewis Acid-Base Interactions of Cations and Anions in Ionic Liquids. <i>Chemistry - A European Journal</i> , 2013, 19, 288-293.	3.3	40
48	ToF-SIMS analysis for leaching studies of potash-lime-silica glass. <i>Applied Surface Science</i> , 2013, 282, 195-201.	6.1	15
49	Thin film cathodes in SOFC research: How to identify oxygen reduction pathways?. <i>Journal of Materials Research</i> , 2013, 28, 2085-2105.	2.6	28
50	Carbon doped $\text{Al}_2\text{O}_3$ coatings grown by chemical vapor deposition. <i>Surface and Coatings Technology</i> , 2012, 206, 4771-4777.	4.8	21
51	Bulk and surface characterization of $\text{In}_2\text{O}_3$ (001) single crystals. <i>Physical Review B</i> , 2012, 85, ...	3.2	62
52	Near-surface transport properties of donor doped $\text{Pb}(\text{ZrTi}_{1-x})\text{O}_3$ (PZT) in an external electric field. <i>Solid State Ionics</i> , 2012, 225, 727-731.	2.7	2
53	Characterisation of sputter deposited niobium and boron interlayer in the copper-diamond system. <i>Surface and Coatings Technology</i> , 2012, 208, 24-31.	4.8	40
54	(Invited) Ion Transfer and Ion Transport in Thin Oxide Films Investigated by Complementary Tracer Diffusion and Impedance Spectroscopy Measurements. <i>ECS Transactions</i> , 2012, 45, 203-212.	0.5	2

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55	Oxide Ion Transport in Donor-Doped $\text{Pb}(\text{Zr}_x\text{Ti}_{1-x})\text{O}_3$ : Near-Surface Diffusion Properties. <i>Journal of the American Ceramic Society</i> , 2012, 95, 1692-1700.	3.8	15
56	Relationship between Cation Segregation and the Electrochemical Oxygen Reduction Kinetics of $\text{La}_{0.6}\text{Sr}_{0.4}\text{CoO}_3$ Thin Film Electrodes. <i>Journal of the Electrochemical Society</i> , 2011, 158, B727-B734.	2.9	183
57	Oxide Ion Transport in Donor-Doped $\text{Pb}(\text{Zr}_x\text{Ti}_{1-x})\text{O}_3$ : The Role of Grain Boundaries. <i>Journal of the American Ceramic Society</i> , 2011, 94, 1173-1181.	3.8	22
58	CO addition in low-pressure chemical vapour deposition of medium-temperature $\text{TiC}_x\text{N}_{1-x}$ based hard coatings. <i>Surface and Coatings Technology</i> , 2011, 206, 1691-1697.	4.8	37
59	Investigation of the oxygen exchange mechanism on Pt yttria stabilized zirconia at intermediate temperatures: Surface path versus bulk path. <i>Electrochimica Acta</i> , 2011, 56, 9727-9740.	5.2	47
60	The effect of bias-temperature stress on $\text{Na}^+$ incorporation into thin insulating films. <i>Analytical and Bioanalytical Chemistry</i> , 2011, 400, 649-657.	3.7	6
61	Oxygen diffusion in grain boundaries: a ToF-SIMS investigation on hot-rolled steel sheets. <i>Analytical and Bioanalytical Chemistry</i> , 2011, 400, 659-663.	3.7	3
62	Measurement of $^{18}\text{O}$ tracer diffusion coefficients in thin yttria stabilized zirconia films. <i>Solid State Ionics</i> , 2011, 184, 23-26.	2.7	25
63	Characterization of the mechanical and thermal interface of copper films on carbon substrates modified by boron based interlayers. <i>Surface and Coatings Technology</i> , 2011, 205, 3729-3735.	4.8	12
64	Oxidation and diffusion study on AlCrVN hard coatings using oxygen isotopes $^{16}\text{O}$ and $^{18}\text{O}$ . <i>Thin Solid Films</i> , 2011, 519, 3974-3981.	1.8	14
65	Surface Cation Segregation and its Effect on the Oxygen Reduction Reaction on Mixed Conducting Electrodes Investigated by ToF-SIMS and ICP-OES. <i>ECS Transactions</i> , 2011, 35, 1975-1983.	0.5	2
66	Monitoring Active and Resistive Zones of SOFC Cathodes by Voltage Driven Tracer Incorporation. <i>ECS Transactions</i> , 2011, 35, 2217-2226.	0.5	2
67	Investigation of ionic liquids under $\text{Bi}^+$ and $\text{Bi}^+$ cluster ions bombardment by ToF-SIMS. <i>Journal of Mass Spectrometry</i> , 2010, 45, 1104-1110.	1.6	7
68	The wetting behaviour of silver on carbon, pure and carburized nickel, cobalt and molybdenum substrates. <i>Applied Surface Science</i> , 2010, 256, 4697-4701.	6.1	23
69	Low friction CrN/TiN multilayer coatings prepared by a hybrid high power impulse magnetron sputtering/DC magnetron sputtering deposition technique. <i>Thin Solid Films</i> , 2010, 518, 5553-5557.	1.8	39
70	On the temperature dependence of Na migration in thin $\text{SiO}_2$ films during ToF-SIMS $\text{O}_2^+$ depth profiling. <i>Applied Surface Science</i> , 2010, 257, 25-32.	6.1	14
71	Investigation of $n$ -butylmethylimidazolium bis(trifluoromethylsulfonyl)imide under $\text{Bi}^+$ cluster ion bombardment. <i>Surface and Interface Analysis</i> , 2010, 42, 1025-1029.	1.8	2
72	Pt-assisted oxidation of (100)-Ge/high- $k$ interfaces and improvement of their electrical quality. <i>Applied Physics Letters</i> , 2010, 97, .	3.3	21

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73	Reduction of the PtGe/Ge Electron Schottky-Barrier Height by Rapid Thermal Diffusion of Phosphorous Dopants. Journal of the Electrochemical Society, 2010, 157, H815.	2.9	9
74	Digital holographic reflectometry. Optics Express, 2010, 18, 3719.	3.4	36
75	Visualization of oxygen reduction sites at Pt electrodes on YSZ by means of <sup>18</sup> O tracer incorporation: the width of the electrochemically active zone. Physical Chemistry Chemical Physics, 2010, 12, 12734.	2.8	38
76	Lanthanum-Zirconate and Lanthanum-Aluminate Based High- $\epsilon^{\prime}$ Dielectric Stacks on Silicon Substrates. Journal of the Electrochemical Society, 2009, 156, G53.	2.9	5
77	Investigation of the Oxygen Exchange Reaction on Pt/YSZ: The Relation between Three Phase Boundaries and Electrode Performance. ECS Transactions, 2009, 25, 2783-2792.	0.5	2
78	Impact of Germanium Surface Conditioning and ALD-growth Temperature on Al[sub 2]O[sub 3]/ZrO[sub 2] High-k Dielectric Stacks. Journal of the Electrochemical Society, 2009, 156, G168.	2.9	6
79	Analysis of antioxidants in insulation cladding of copper wire: a comparison of different mass spectrometric techniques (ESI-IT, MALDI-TOF and TOF-SIMS). Journal of Mass Spectrometry, 2009, 44, 1724-1732.	1.6	10
80	TOF-SIMS depth profiling and element mapping on oxidized AlCrVN hard coatings. Analytical and Bioanalytical Chemistry, 2009, 393, 1857-1861.	3.7	8
81	Investigation of polymer thin films by use of Bi-cluster-ion-supported time of flight secondary ion mass spectrometry. Analytical and Bioanalytical Chemistry, 2009, 393, 1889-1898.	3.7	9
82	Suppression of de-wetting of copper coatings on carbon substrates by metal (Cr, Mo, Ti) doped boron interlayers. Vacuum, 2009, 84, 202-204.	3.5	5
83	TOF-SIMS investigations on weathered silver surfaces. Analytical and Bioanalytical Chemistry, 2008, 390, 1543-1549.	3.7	14
84	TOF-SIMS investigations on thermally treated copper-molybdenum films on a carbon substrate. Analytical and Bioanalytical Chemistry, 2008, 390, 1537-1541.	3.7	2
85	Novel monodisperse PEG-grafted polystyrene resins: synthesis and application in gel-phase <sup>13</sup> C NMR spectroscopy. Tetrahedron Letters, 2008, 49, 7103-7105.	1.4	5
86	Initial oxidation of silver surfaces by S <sub>2</sub> <sup>-</sup> and S <sub>4</sub> <sup>+</sup> species. Corrosion Science, 2008, 50, 1112-1121.	6.6	64
87	Characterisation of molybdenum intermediate layers in Cu-C system with SIMS method. Applied Surface Science, 2005, 252, 266-270.	6.1	9
88	Range evaluation in SIMS depth profiles of Er-implantations in silicon. Applied Surface Science, 2005, 252, 271-277.	6.1	13
89	Influences of the nitrogen content on the morphological, chemical and optical properties of pulsed laser deposited silicon nitride thin films. Surface and Coatings Technology, 2005, 192, 225-230.	4.8	8
90	Low energy RBS and SIMS analysis of the SiGe quantum well. Applied Surface Science, 2005, 252, 123-126.	6.1	4

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91	Investigations of corrosion phenomena on gold coins with SIMS. Applied Surface Science, 2005, 252, 133-138.	6.1	12
92	SIMS investigation of gettering centres produced by phosphorus MeV ion implantation. Applied Surface Science, 2005, 252, 278-281.	6.1	4
93	2D and 3D SIMS investigations on sintered steels. Applied Surface Science, 2005, 252, 282-285.	6.1	4
94	Quantitative analysis of the Ge concentration in a SiGe quantum well: comparison of low-energy RBS and SIMS measurements. Analytical and Bioanalytical Chemistry, 2005, 384, 525-530.	3.7	4
95	Investigation of gettering effects in CZ-type silicon with SIMS. Analytical and Bioanalytical Chemistry, 2005, 381, 1526-1531.	3.7	3
96	Quantitative SIMS depth profiling of diffusion barrier gate-oxynitride structures in TFT-LCDs. Analytical and Bioanalytical Chemistry, 2004, 379, 599-604.	3.7	4
97	Characterization of the distribution of the sintering activator boron in powder metallurgical steels with SIMS. Analytical and Bioanalytical Chemistry, 2004, 379, 605-9.	3.7	8
98	Phosphorus as sintering activator in powder metallurgical steels: characterization of the distribution and its technological impact. Analytical and Bioanalytical Chemistry, 2004, 379, 610-8.	3.7	8
99	Characterisation of the interface of sputter-deposited copper coatings on nitrogen plasma-treated carbon substrates. Analytical and Bioanalytical Chemistry, 2004, 380, 838-842.	3.7	3
100	Investigations on the effects of plasma-assisted pre-treatment for plasma-assisted chemical vapour deposition TiN coatings on tool steel. Thin Solid Films, 2004, 461, 277-281.	1.8	27
101	AES and SIMS analysis of non-metallic inclusions in a low-carbon Chromium-steel. Analytical and Bioanalytical Chemistry, 2003, 376, 255-259.	3.7	4
102	SIMS Investigations on the Distribution of Trace Elements in Modified Aluminium-Silicon-Magnesium Alloys. Mikrochimica Acta, 2003, 141, 23-27.	5.0	8
103	Cu gettering in ion implanted and annealed silicon in regions before and beyond the mean projected ion range. Journal of Applied Physics, 2003, 94, 3834-3839.	2.5	12
104	SIMS and TM-AFM Studies on Weathered Cu, Zn, and Brass (CuZn10, CuZn30) Surfaces. Instrumentation Science and Technology, 2003, 21, 49-62.	0.8	10
105	Influence of increasing zinc contents in brass in the early stages of corrosion investigated by in-situ TM-AFM and SIMS. Analytical and Bioanalytical Chemistry, 2002, 374, 338-343.	3.7	15
106	2D- and 3D SIMS investigations on hot-pressed steel powder HS 6-5-3-8. Analytical and Bioanalytical Chemistry, 2002, 374, 597-601.	3.7	4
107	Chemical solution-deposited $\text{PbZr}_{0.53}\text{Ti}_{0.47}\text{O}_3$ on $\text{La}_{0.5}\text{Sr}_{0.5}\text{CoO}_3$ . SIMS investigation of the effect of different precursor additives on the layer structure. Analytical and Bioanalytical Chemistry, 2002, 374, 608-613.	3.7	3
108	Adhesion promotion of Cu on C by Cr intermediate layers investigated by the SIMS method. Analytical and Bioanalytical Chemistry, 2002, 374, 602-607.	3.7	15

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109	SIMS investigation of CrN sputtercoatings. <i>Analytical and Bioanalytical Chemistry</i> , 2002, 374, 592-596.	3.7	4
110	Comparative study of LNO, LSCO and LSMO as electrode layers for microelectronic capacitors by dynamic SIMS. <i>Surface and Coatings Technology</i> , 2002, 150, 119-124.	4.8	10
111	INVESTIGATIONS ON CODEPOSITED ALUMINUM-TIN SYSTEMS WITH SIMS. <i>Instrumentation Science and Technology</i> , 2001, 19, 91-98.	0.8	5
112	Clarification by TEM and SIMS of abnormal Ti depth distribution in chemical solution-deposited SrTiO <sub>3</sub> /La <sub>0.5</sub> Sr <sub>0.5</sub> CoO <sub>3</sub> . <i>Fresenius' Journal of Analytical Chemistry</i> , 2001, 371, 54-57.	1.5	1
113	Characterization of the 3D-distribution of the components in Al-alloyed high speed steels with SIMS. <i>Applied Surface Science</i> , 2001, 179, 240-244.	6.1	8
114	Characterisation of Cr intermediate layers in Cu-C-system with SIMS method. <i>Applied Surface Science</i> , 2001, 179, 275-280.	6.1	10
115	Microstructural characterisation of five simulated archaeological copper alloys using light microscopy, scanning electron microscopy, energy dispersive X-ray microanalysis and secondary ion mass spectrometry. <i>Analytica Chimica Acta</i> , 2001, 440, 189-198.	5.4	23
116	SIMS: a capable method for BCN quantification. <i>Applied Surface Science</i> , 2000, 167, 79-88.	6.1	7
117	Local Ions Distribution Inhomogeneities in Polymer Based Light Emitting Cells. <i>Mikrochimica Acta</i> , 2000, 135, 131-137.	5.0	5
118	Characterization of the Element Distribution Within TiN Coatings with SIMS. <i>Mikrochimica Acta</i> , 2000, 135, 105-111.	5.0	3
119	Quantitative Sputter Depth Profiling of Silicon- and Aluminium Oxynitride Films. <i>Mikrochimica Acta</i> , 2000, 133, 75-87.	5.0	3
120	Investigations on the Thermal Cycling Stability of SiFeCr Coated NbtZr. <i>Mikrochimica Acta</i> , 2000, 133, 89-93.	5.0	3
121	Application of SIMS in Re-Technology Studies: Characterization of Trace-Element Distributions and Quantitative of Carbon-Determination. <i>Mikrochimica Acta</i> , 2000, 133, 253-259.	5.0	2
122	SIMS Characterisation of Aluminum-Alloyed Hot Isostatic Pressed Steel. <i>Mikrochimica Acta</i> , 2000, 133, 261-266.	5.0	7
123	Characterization of Two-Component Metal Coatings (Al/Sn) with SIMS. <i>Mikrochimica Acta</i> , 2000, 133, 267-271.	5.0	8
124	Fusion of 2-D SIMS Images Using the Wavelet Transform. <i>Mikrochimica Acta</i> , 2000, 133, 273-278.	5.0	11
125	Compression of Secondary Ion Microscopy Image Sets Using a Three-dimensional Wavelet Transformation. <i>Microscopy and Microanalysis</i> , 2000, 6, 68-75.	0.4	4
126	WC-Co substrate surface pretreatments with aluminum compounds prior to polycrystalline CVD diamond deposition. <i>International Journal of Refractory Metals and Hard Materials</i> , 1999, 17, 445-452.	3.8	16



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127	Charge distribution in light emitting electrochemical cells. <i>Synthetic Metals</i> , 1999, 102, 1022-1023.	3.9	7
128	Channelplate Illumination Correction for Secondary Ion Mass Spectroscopy Images by Solving Apparatus Elasticity Equations. <i>Microscopy and Microanalysis</i> , 1999, 5, 407-412.	0.4	2
129	The wavelet transform: A new preprocessing method for peak recognition of infrared spectra. <i>Mikrochimica Acta</i> , 1998, 128, 241-250.	5.0	10
130	Visualization of n-dimensional analytical data on personal computers <sup>1</sup> The images in this article can be viewed in colour at <a href="http://www.elsevier.nl/locate/trac">http://www.elsevier.nl/locate/trac</a> . Click on the Supplementary material link.1. <i>TrAC - Trends in Analytical Chemistry</i> , 1998, 17, 120-128.	11.4	3
131	Investigation of the formation and properties of protective oxide layers on high purity chromium with SIMS imaging techniques. <i>Mikrochimica Acta</i> , 1997, 125, 69-72.	5.0	4
132	Classification of secondary ion mass spectrometry (SIMS) micrographs to characterize chemical phases. <i>Mikrochimica Acta</i> , 1995, 119, 1-12.	5.0	6
133	Maximum entropy deconvolution of AFM and STM images. <i>Fresenius' Journal of Analytical Chemistry</i> , 1995, 351, 143-147.	1.5	9
134	Imaging SIMS for the investigation of substrate surfaces for CVD diamond deposition. <i>Fresenius' Journal of Analytical Chemistry</i> , 1995, 352, 313-317.	1.5	3
135	3D-SIMS analysis of ultra high purity molybdenum and tungsten: a characterisation of different manufacturing techniques and products. <i>Fresenius' Journal of Analytical Chemistry</i> , 1995, 353, 524-532.	1.5	11
136	SAM investigations of temperature programmed surface segregation of impurities in $\alpha$ -iron. <i>Fresenius' Journal of Analytical Chemistry</i> , 1995, 353, 762-765.	1.5	6
137	Maximum entropy deconvolution of secondary ion mass spectra with a measured response. <i>Fresenius' Journal of Analytical Chemistry</i> , 1994, 349, 186-190.	1.5	6
138	Automatic matching of SAM, SIMS and EPMA images. <i>Fresenius' Journal of Analytical Chemistry</i> , 1994, 349, 197-199.	1.5	4
139	Trends in surface and interface analysis. <i>Fresenius' Journal of Analytical Chemistry</i> , 1993, 346, 594-603.	1.5	17
140	Topochemical characterization of materials using 3D-SIMS. <i>Fresenius' Journal of Analytical Chemistry</i> , 1993, 346, 66-68.	1.5	15
141	Three dimensional ultra trace analysis of materials. <i>Mikrochimica Acta</i> , 1992, 107, 137-148.	5.0	41
142	Characterization of oxygen precipitates in Czochralski silicon by imaging SIMS. <i>Mikrochimica Acta</i> , 1992, 107, 149-160.	5.0	3
143	Quantitative characterization of oxygen precipitates in CZ-silicon with secondary ion mass spectrometry. <i>Fresenius' Journal of Analytical Chemistry</i> , 1991, 341, 112-115.	1.5	2